## SN74ALVCH16828 **20-BIT BUFFER/DRIVER** WITH 3-STATE OUTPUTS SCES042 - JULY 1995

Bus Hold on Data Inputs Eliminates the 1Y2 [ 3 54 ]     Need for External Pullup/Pulldown     GND [ 4 53 ]	1A1 1A2 GND
<ul> <li>Bus Hold on Data Inputs Eliminates the 1Y2 3 54 GND 4 53</li> <li>Need for External Pullup/Pulldown GND 4 53</li> </ul>	1A2 GND
	1A.3
<ul> <li>Package Options Include Plastic 300-mil</li> <li>Shrink Small-Outline (DL) and Thin Shrink</li> <li>Small-Outline (DGG) Packages</li> <li>1Y5 [ 8 49 ]</li> </ul>	1A4 V <sub>CC</sub> 1A5
	the $1OE1$ $1$ $56$ $1OE2$ $1Y1$ $2$ $55$ $1A1$ $1Y2$ $3$ $54$ $1A2$ $GND$ $4$ $53$ $GND$ $1Y3$ $5$ $52$ $1A3$ $0$ -mil $1Y4$ $6$ $51$ $1A4$ Shrink $V_{CC}$ $7$ $50$ $V_{CC}$ $1Y5$ $8$ $49$ $1A5$ $1Y6$ $9$ $48$ $1A6$ $1Y7$ $10$ $47$ $1A7$ $Signed$ for $GND$ $11$ $46$ $1Y7$ $10$ $47$ $1A7$ $signed$ for $GND$ $11$ $46$ $1Y7$ $10$ $47$ $1A7$ $signed$ for $GND$ $11$ $46$ $1Y9$ $13$ $44$ $1A9$ two 10-bit $1Y10$ $14$ $43$ $1Y9$ $13$ $44$ $1A9$ two 10-bit $2Y1$ $15$ $42$ $2A1$ $2Y2$ $16$ $41$ $2A2$ $2Y3$ $17$ $40$ $2A3$ $2X3$ $2X4$ $2y3$ $17$ $40$ $2A3$ $2A4$ $2y6$ $21$ $36$ $2y6$ $21$ $36$ $2y6$ $21$ $36$ $2y6$ $23$ $4$ $2y7$ $23$ $34$ $2A7$ $2x8$ $2y8$ $24$ $33$ $2A8$
2.3-V to 3.6-V $V_{CC}$ operation. 1Y8 $\begin{bmatrix} 12 & 45 \end{bmatrix}$	1A8
The SN74ALVCH16828 is composed of two 10-bit1Y101443sections with separate output-enable signals. For either 10-bit buffer section, the two output-enable (1OE1 and 1OE2 or 2OE1 and 2OE2) inputs must both be low for the corresponding Y outputs to be active. If either output-enable input is high, the outputs of that 10-bit buffer section are in the bidb-impedance state144314431542164117401839273171839274192752027520	1A10 2A1 2A2 2A3 GND 2A4 2A5
To ensure the high-impedance state during powerV <sub>CC</sub> 2235up or power down, OE should be tied to V <sub>CC</sub> 2Y72334through a pullup resistor; the minimum value of2Y82433the resistor is determined by the current-sinkingGND2532capability of the driver.2Y92631	V <sub>CC</sub> 2A7 2A8 GND 2A9

Active bus-hold circuitry is provided to hold unused or floating inputs at a valid logic level.

The SN74ALVCH16828 is available in TI's shrink small-outline (DL) and thin shrink small-outline (DGG) packages, which provide twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

20E1 28

29

20E2

The SN74ALVCH16828 is characterized for operation from -40°C to 85°C.

#### **FUNCTION TABLE** (each 10-bit section) INPUTS OUTPUT Υ OE1 OE2 Α L Н L L L L Н L Ζ н Х Х Х н Х Ζ



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#### logic symbol<sup>†</sup>



### logic diagram (positive logic)



To Nine Other Channels



**To Nine Other Channels** 

<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



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#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage range, V <sub>CC</sub>	–0.5 V to 4.6 V
Input voltage range, V <sub>I</sub> (see Note 1)	
Output voltage range, V <sub>O</sub> (see Notes 1 and 2)	$\dots$ -0.5 V to V <sub>CC</sub> + 0.5 V
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0)	–50 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$ )	±50 mA
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	±50 mA
Continuous current through each V <sub>CC</sub> or GND	±100 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 3): DGG package	e 1 W
DL package	1.4 W
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. This value is limited to 4.6 V maximum.

3. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the Package Thermal Considerations application note in the 1994 ABT Advanced BiCMOS Technology Data Book, literature number SCBD002B.

#### recommended operating conditions (see Note 4)

			MIN	MAX	UNIT	
VCC	Supply voltage			3.6	V	
V	High lovel input veltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7		V	
VIH	High-level input voltage	$V_{CC} = 2.7 V \text{ to } 3.6 V$	2		v	
	Low-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		0.7	v	
VIL		$V_{CC} = 2.7 V \text{ to } 3.6 V$		0.8	v	
VI	Input voltage		0	VCC	V	
VO	Output voltage		0	VCC	V	
Iон	High-level output current	V <sub>CC</sub> = 2.3 V		-12	_	
		$V_{CC} = 2.7 V$		-12		
		$V_{CC} = 3 V$		-24		
	Low-level output current	V <sub>CC</sub> = 2.3 V		12	mA	
IOL		$V_{CC} = 2.7 V$		12		
		$V_{CC} = 3 V$		24		
$\Delta t/\Delta v$	Input transition rise or fall rate		0	10	ns/V	
Т <sub>А</sub>	Operating free-air temperature		-40	85	°C	

NOTE 4: Unused control inputs must be held high or low to prevent them from floating.



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#### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PAR	AMETER	TEST CO	ONDITIONS	vcc†	MIN TYP <sup>‡</sup>	MAX	UNIT
Vон		I <sub>OH</sub> = –100 μA		MIN to MAX	V <sub>CC</sub> -0.2		
		I <sub>OH</sub> = -6 mA,	V <sub>IH</sub> = 1.7 V	2.3 V	2.0		
		I <sub>OH</sub> = -12 mA	V <sub>IH</sub> = 1.7 V	2.3 V	1.7		V
			V <sub>IH</sub> = 2 V	2.7 V	2.2		
			V <sub>IH</sub> = 2 V	3 V	2.4		
		I <sub>OH</sub> = -24 mA,	V <sub>IH</sub> = 2 V	3 V	2		
		l <sub>OL</sub> = 100 μA		MIN to MAX		0.2	
		I <sub>OL</sub> = 6 mA,	V <sub>IL</sub> = 0.7 V	2.3 V		0.4	
VOL			V <sub>IL</sub> = 0.7 V	2.3 V		0.7	V
		I <sub>OL</sub> = 12 mA	V <sub>IL</sub> = 0.8 V	2.7 V		0.4	
		I <sub>OL</sub> = 24 mA,	V <sub>IL</sub> = 0.8 V	3 V		0.55	
lj		V <sub>I</sub> = V <sub>CC</sub> or GND		3.6 V		±5	μA
I <sub>I(hold)</sub>		V <sub>I</sub> = 0.7 V		0.01/	45		μΑ
		V <sub>I</sub> = 1.7 V		2.3 V	-45		
		V <sub>I</sub> = 0.8 V		0.)/	75		
		V <sub>I</sub> = 2 V		3 V	-75		
		V <sub>I</sub> = 0 to 3.6 V		3.6 V		±500	
loz		V <sub>O</sub> = V <sub>CC</sub> or GND		3.6 V		±10	μA
ICC		$V_{I} = V_{CC}$ or GND,	IO = 0	3.6 V		40	μA
∆ICC		One input at V <sub>CC</sub> – 0.6 V,	Other inputs at V <sub>CC</sub> or GND	3 V to 3.6 V		750	μA
	Control inputs			0.0.1/	3	-	
C <sub>i</sub>	Data inputs	$V_{I} = V_{CC}$ or GND		3.3 V	6		pF
Co	Outputs	$V_{O} = V_{CC}$ or GND		3.3 V	7		pF

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate values under recommended operating conditions.

<sup>‡</sup>Typical values are measured at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C.



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